



Ellipsometry - Basic Level

Reference

ELL1

Price per attendee

For 2 days 1 210€ For 3 days 1 815€

Duration

2 days + 1 day optional

Date

27-29 March and 11-13 September 2024

Registration deadline

27 February and 11 August 2024

Location

14 Boulevard Thomas Gobert, 91120 Palaiseau - France

Prerequisites

Dedicated to HORIBA customers only and knowledge of the technique and equipment.

Who should attend

New users of HORIBA ellipsometers.

Certification

A diploma is delivered at the end of the course.

Learning method

Theoretical presentation and instrument practice.

Course language

English

Objectives

- Provides a thorough background in the basic ellipsometry theory and focus on modelling techniques with a large variety of hands-on sample analysis.
- Use of the ellipsometer and DeltaPsi2 software through a large variety of hands-on sample analysis.



PROGRAM

Day 1

Theory and Practical:

- · Ellipsometry theory
- · Instrumentation
- · Overview of modelling process
- Description of main functions of DeltaPsi2 software & hands on the ellipsometer
- · Procedure to check the system before to perform measurements
- · Measurement and modelling of transparent films on opaque substrates

Day 2

Practical Session & Software Use:

- Sample analysis of semi-absorbing thin films in monolayers and multilayers of opaque substrate
- · EMA, roughness
- · Sample analysis of glass substrate
- · Sample analysis of semi-absorbing thin films on glass
- · Sample analysis of absorbing films
- · Dispersion formulae parameterization
- · Sample analysis of thickness of non-uniform layers

Day 3 (optional)

Practical Session with customer samples